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MOCVD OF HIGH QUALITY LuBa₂Cu₃O_{7- δ} THIN FILMS

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Epitaxial LuBa₂Cu₃O_{7- δ} films were prepared by flash evaporation MOCVD on LaAlO₃, SrTiO₃, LaSrGaO₄ and ZrO₂(Y₂O₃) single crystalline substrates. The highest T_c and j_c (77 K, 100 Oe) values were 89 K, 2.7×10^6 A/cm² (LaAlO₃) and 88 K, 1.5×10^6 A/cm² (SrTiO₃) respectively. The occurrence of secondary phases inclusions in LuBa₂Cu₃O_{7- δ} films correlates with the possibility of epitaxial relations with the film matrix or the substrate.

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It is well known that single phase LuBa₂Cu₃O_{7- δ} ceramics cannot be obtained. However, single crystals of LuBa₂Cu₃O_{7- δ} were successfully grown by self-flux technique [1]. LuBa₂Cu₃O_{7- δ} phase can be also obtained as a thin film by pulsed laser deposition (PLD) and MOCVD [2, 3]. Peculiarities of RBa₂Cu₃O_{7- δ} phase with R³⁺ of the smallest ionic radius (Lu³⁺) are important for better understanding of properties of the whole R-series. In the paper we report our recent results on structural and superconducting characteristics of LuBa₂Cu₃O_{7- δ} thin films prepared by MOCVD.

Epitaxial LuBa₂Cu₃O_{7- δ} films on LaAlO₃ (001), SrTiO₃ (001), LaSrGaO₄ (001) and ZrO₂(Y₂O₃) (001) single crystal substrates were prepared by flash evaporation MOCVD as described elsewhere [3]. X-ray diffraction (XRD) study of the films (DRON-3M, SIEMENS D5000 diffractometers) was used to determine phase composition, orientation and lattice parameter c of LuBa₂Cu₃O_{7- δ} . Cation stoichiometry was determined using EDX analysis and sputtered neutral mass spectrometry (SNMS) (Leybold INA-3). AC susceptibility measurements ($\chi(T)$) were performed in the range of 10–100 K using APD Cryogenics magnetometer. $j_c(T)$ dependences were found from the imaginary part of $\chi(T)$ as described in [4]. Scanning electron microscopy (SEM) with Jeol JEM-2000 FXII was used to study the films surface morphology. Transmission electron microscopy (TEM) studies of the films were performed with a Philips CM30ST electron microscope operating

at 300 kV. Atomic force microscopy (AFM) experiments were carried out with NANOSCOPE.

It is widely known that j_c , T_c , lattice parameter c and some other characteristics of $\text{YBa}_2\text{Cu}_3\text{O}_{7-\delta}$ thin films are strongly dependent on deposition temperature and $p(\text{O}_2)$ [5–7]. The dependences of $j_c(77\text{ K})$ and c values of $\text{LuBa}_2\text{Cu}_3\text{O}_{7-\delta}$ thin films prepared at $T = 800^\circ\text{C}$ on LaAlO_3 (001) and SrTiO_3 (001) substrates on $p(\text{O}_2)$ reveal the optimum value of 1.05 ± 0.10 Tr in the investigated range of 0.82–1.5 Tr. The similar dependences were found for FWHM of (00 l) peaks and T_c values, however, the dependence is less profound for T_c , in agreement with the results of [5].

The increase in c parameter originates from a higher defect density in crystal structure of the film [6, 7]. The defect density increases with approaching growth conditions to the stability border of $\text{LuBa}_2\text{Cu}_3\text{O}_{7-\delta}$ ($p(\text{O}_2)$ lower than optimal) and with reducing of cation mobility during the growth ($p(\text{O}_2)$ higher than optimal). The optimum $p(\text{O}_2)$ is quite close to that of $\text{CuO}/\text{Cu}_2\text{O}$ equilibrium, the similar behaviour is known for $\text{YBa}_2\text{Cu}_3\text{O}_{7-\delta}$ [5].

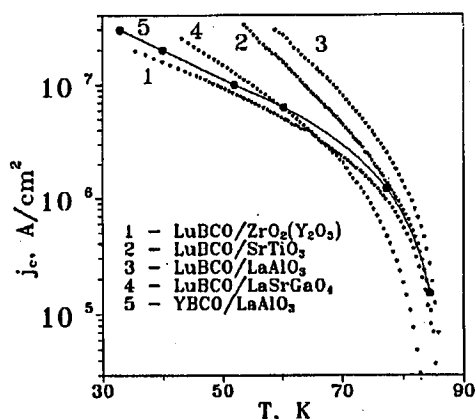


Fig. 1. Temperature dependences of j_c of $\text{LuBa}_2\text{Cu}_3\text{O}_{7-\delta}$ thin films on different substrates and $\text{YBa}_2\text{Cu}_3\text{O}_{7-\delta}$ film on LaAlO_3 as a reference.

The temperature dependences of j_c of $\text{LuBa}_2\text{Cu}_3\text{O}_{7-\delta}$ thin films on LaAlO_3 and SrTiO_3 grown under the optimum conditions are compared in Fig. 1. The higher j_c in the films on LaAlO_3 reflects the smaller lattice mismatch with $\text{LuBa}_2\text{Cu}_3\text{O}_{7-\delta}$. Using dependences of a and b parameters for $\text{RBa}_2\text{Cu}_3\text{O}_7$ on R^{3+} radii, derived from structural data in [8], $a = 3.80\text{ \AA}$ and $b = 3.87\text{ \AA}$ were found for $\text{R} = \text{Lu}$. Thus, the mismatch of $\text{LuBa}_2\text{Cu}_3\text{O}_{7-\delta}$ $(a + b)/2$ parameter with a pseudocubic lattice parameter of LaAlO_3 , SrTiO_3 and $\text{ZrO}_2(\text{Y}_2\text{O}_3)$ is 1.1%, 1.8% and 6% respectively. The increase in j_c with a temperature decrease is much steeper for $\text{LuBa}_2\text{Cu}_3\text{O}_{7-\delta}$ films than for $\text{YBa}_2\text{Cu}_3\text{O}_{7-\delta}$ in agreement with the observations for PLD films [9]. The film on LaSrGaO_4 ($a = 3.84\text{ \AA}$) was deposited under conditions optimized for LaAlO_3 . Some contribution of a -oriented phase deteriorating superconducting characteristics was detected by XRD in the film.

A surface morphology of $\text{LuBa}_2\text{Cu}_3\text{O}_{7-\delta}$ films on LaAlO_3 and SrTiO_3 substrates reveals two specific features: (1) an absence of a -oriented $\text{LuBa}_2\text{Cu}_3\text{O}_{7-\delta}$ crystallites of the distinctive elongated shape on the film surface (in agreement with XRD study), irrespective of the film thickness and deposition $p(\text{O}_2)$ used; (2) a significant disturbance of $\text{LuBa}_2\text{Cu}_3\text{O}_{7-\delta}$ matrix flatness. According to AFM study, the outgrowths of $\text{LuBa}_2\text{Cu}_3\text{O}_{7-\delta}$ observed were about 1000 Å in height at a film thickness of 3000 Å.

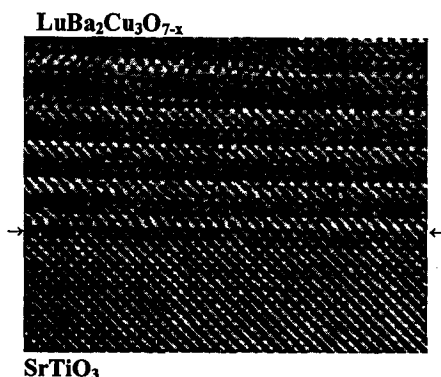


Fig. 2. TEM microphotograph of an interface area of $\text{LuBa}_2\text{Cu}_3\text{O}_{7-\delta}/\text{SrTiO}_3$.

TEM study of films on LaAlO_3 and SrTiO_3 revealed an epitaxial film-substrate interface (Fig. 2) with lattice mismatch resolved by the misfit dislocations. Any deviations of a cation composition of the film from the stoichiometry of $\text{LuBa}_2\text{Cu}_3\text{O}_{7-\delta}$ phase led to an appearance of inclusions of other phases. Usually observed secondary phases in the films were CuO , BaCuO_2 , Lu_2O_3 and $\text{Lu}_2\text{Cu}_2\text{O}_5$. The presence of all these phases was proved by XRD also, except for the $\text{Lu}_2\text{Cu}_2\text{O}_5$ inclusions observed by TEM only. An occurrence of the secondary phase inclusions depends on the possibility of epitaxial relations with $\text{LuBa}_2\text{Cu}_3\text{O}_{7-\delta}$ matrix or substrate (Table). If no epitaxial relation takes place, the inclusion tends to appear on the film surface. Thus, protruding CuO precipitates of a size up to 1 μm were often observed on the film surface, this means that CuO impurity tends to be pushed out of the growing film. A density of the $\text{LuBa}_2\text{Cu}_3\text{O}_{7-\delta}$ outgrowths decreases drastically near CuO precipitates, probably an enhanced surface cation mobility takes place in the copper-enriched regions [10].

R_2O_3 and $\text{R}_2\text{Cu}_2\text{O}_5$ are generally considered to be non-equilibrium phases to $\text{RBa}_2\text{Cu}_3\text{O}_{7-\delta}$ [11, 12]. To explain their presence in the film, the following reasons can be proposed: (1) a contribution of surface energy could change an equilibrium phase diagram; (2) non-equilibrium phases could be nucleated in the gas phase [13] and afterwards be stabilized kinetically due to the epitaxial relations with $\text{RBa}_2\text{Cu}_3\text{O}_{7-\delta}$ (Fig. 3).

Concluding, the influence of the deposition $p(\text{O}_2)$ conditions on the properties of $\text{LuBa}_2\text{Cu}_3\text{O}_{7-\delta}$ films is rather similar to that in the case of $\text{YBa}_2\text{Cu}_3\text{O}_{7-\delta}$ films. The occurrence and orientation of secondary phase inclusions in

TABLE

Secondary phases, their occurrence and epitaxial relations to $\text{LuBa}_2\text{Cu}_3\text{O}_{7-\delta}$ or substrate (LaAlO_3).

Phase	Syngony, lattice parameters	Occurrence	Orientation
CuO	monoclinic, $a = 4.685 \text{ \AA}$, $b = 3.423 \text{ \AA}$, $c = 5.132 \text{ \AA}$, $\beta = 99.52^\circ$	film surface	random
BaCuO ₂	cubic, $a = 18.285 \text{ \AA}$	film surface or inside LuBCO matrix	no data
Lu ₂ O ₃	cubic, $a = 10.39 \text{ \AA}$	film-substrate interface or inside LuBCO matrix	(001) _{LuBCO} (001) _{Lu₂O₃} , (100) _{LuBCO} (110) _{Lu₂O₃}
Lu ₂ Cu ₂ O ₅	orthorhombic, $a = 10.698 \text{ \AA}$, $b = 3.4102 \text{ \AA}$, $c = 12.358 \text{ \AA}$	film-substrate interface	(01-1) _{LaAlO₃} (001) _{Lu₂Cu₂O₅} , (011) _{LaAlO₃} (013) _{Lu₂Cu₂O₅}



Fig. 3. Coherent Lu_2O_3 inclusion in the matrix of $\text{LuBa}_2\text{Cu}_3\text{O}_{7-\delta}$ film.

$\text{LuBa}_2\text{Cu}_3\text{O}_{7-\delta}$ films correlate with a possibility of epitaxial relations with $\text{LuBa}_2\text{Cu}_3\text{O}_{7-\delta}$ matrix or the substrate.

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